

<b>Searched</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10661816	MUCHOW ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

Class	SubClass	Date	Examiner
307	72	10/12/2006	HK
320	101	10/12/2006	HK

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<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
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EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TD B) - See Search History Printout	10/12/2006	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TD B) - See Search History Printout	10/18/2006	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TD B) - See Search History Printout	10/19/2006	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TD B) - See Search History Printout	10/20/2006	HK
361/600+; 220/\$ (consulted Boris Chervinsky)	10/19/2006	HK
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